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Underapproximation for model-checking based on universal circuits

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ABSTRACT

For two naturals m, n such that $m < n$, we show how to construct a circuit C with m inputs and n outputs, that has the following property: for some $0 \leqslant k \leqslant m$, the circuit defines a k-universal function. This means, informally, that for every subset K of k outputs, every possible valuation of the variables in K is reachable.

Now consider a circuit M with n inputs that we wish to model-check. Connecting the inputs of M to the outputs of C gives us a new circuit M' with m inputs, that its original inputs have freedom defined by k. This is a very attractive feature for underapproximation in model-checking: on one hand the combined circuit has a smaller number of inputs, and on the other hand it is expected to find an error state fast if there is one.

We show a random construction of a k-universal circuit that guarantees that k is very close to m, with an arbitrarily high probability. We also present a deterministic construction of such a circuit, but here the value of k is smaller with respect to a fixed value of m. We report initial experimental results with bounded model-checking of industrial designs (the method is equally applicable to unbounded model-checking and to simulation), which shows mixed results. An interesting observation, however, is that in 13 out of 17 designs, setting m to be $n/5$ is sufficient to detect the bug. This is in contrast to other underapproximation techniques that are based on reducing the number of inputs, which in most cases cannot detect the bug even with $m = n/2$.

1. Introduction

Experience with model-checking of industrial hardware designs shows that when the model violates a specification, it is frequently the case that the values of only some of the inputs is important for triggering an erroneous behavior (as the saying goes: "when it rains – it pours!"). Based on this observation it is appealing to underapproximate the model, attempting to make it easier to check, yet not eliminating the problematic behavior altogether. In other words, the challenge is to underapproximate by finding those restrictions that do not prevent all error states from being reached. Designing a fully automatic model-checking algorithm based on underapproximation that is still sound and complete requires an iterative process of underapproximation and refinement.

Automatic underapproximation/refinement for model-checking is not nearly as popular as its dual, automated over-approximation/refinement. An overapproximating abstraction may result in a false negative, accompanied by a spurious (abstract) counterexample. This counterexample can then be used to guide the refinement process, as in the CEGAR [1–4] and proof-based [5] frameworks (in the latter only the length of the counterexample is used). All of these works are based on overapproximation.

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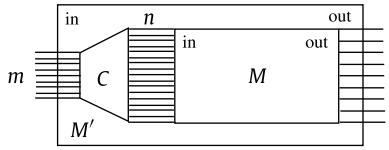

Fig. 1. Since the attached Boolean circuit is k-universal, *any* assignment on *any* k out of the n inputs of the original model M, can be achieved under some assignment on the inputs of M'.

An underapproximation, on the other hand, may result in a false positive: here, good refinements are harder to achieve, as there is no equivalent to the counterexample that can guide it. An exception to this rule is in SAT-based Bounded Model-Checking (BMC), where the unsatisfiable core can guide the refinement: Grumberg et al. [6] used this fact in their work on underapproximation–refinement for bounded model-checking of multi-process systems. We are only aware of few works on underapproximations with BDDs (e.g., [7–9]), all of which are based on the size of the BDD (e.g., restricting the growth of the reachable state-space when the BDD size becomes too large), but none of them are fully automatic and complete.

In this paper we focus on underapproximations that are based on reducing the number of inputs to the model. In theory this should make the model easier to solve, at least in the worst-case, since the number of computation paths has exponential dependency on the number of inputs.[1] The most basic technique is to restrict some of the inputs to constants. Such naive underapproximation, combined with a gradual lifting of these restrictions (typically in a manual manner) is a common practice in the industry probably from the very first days of industrial model-checking. If no user-guidance is provided, however, an automated refinement based on some arbitrary order of lifting the restrictions has a small chance to succeed, unless the bug is ubiquitous enough to be very simple to find. It is enough for one of the inputs necessary for exposing the error-trace to be falsely restricted, to potentially make the model too big for model-checking by the time this input is released. Another option is to combine inputs (arbitrarily) and refining by splitting the combined sets. In Section 2.2 we analyze these options in more depth.

What is this article about? The current work suggests an underapproximation which reduces the number of inputs as well, but it is based on adding circuitry to the model, while maintaining a measurable and uniform degree of freedom to the original inputs. This technique is automatic, easy to combine in an underapproximation–refinement method, and is applicable to any form of model-checking or simulation, whether it is SAT-based or BDD-based. The technique is inspired by theoretical constructions of cryptographic circuits, the Pseudo Random Generators (PRGs). These PRGs can expand a short truly random Boolean sequence into a longer one, which is almost random (more details are given in Section 2). Based on constructions of these PRGs, we build simple Boolean circuits and prove that they have the universality property as defined below.

Consider a model M with n inputs that we wish to model-check. We build a Boolean circuit with m inputs and n outputs, $0 < m < n$, which is k-universal. Informally, this means that the circuit implements a function such that any valuation of at most k outputs can be reached under some assignment to the inputs. We then connect the outputs of C to the inputs of M (see Fig. 1). The composed model M' has fewer inputs and underapproximates the original model M. One of the challenges in such a construction is to guarantee high values of k for a given value of m. We discuss this question in detail in Section 3.1.

Universality was also used in [11], in the context of simulation. The authors constructed vectors that have a certain degree of universality and showed that this indeed has a better chance to expose problems in comparison to alterative vector sets of the same size. The main contribution of this paper is theoretical: we show how to construct M' and derive lower-bounds on the value of k as a function of m. Since the construction is based on a random function, the results are probabilistic. We also define a weaker version of universality, called (k, ϵ)-universality, in which for only a $1 - \epsilon$ fraction of the subsets of size k, any assignment is possible (k-universality corresponds to $\epsilon = 0$). With this relaxation we prove that for $k = \max(0, m - \log \frac{1}{\epsilon \cdot \delta})$, where δ is the confidence level, the circuit C is (k, ϵ)-universal with probability at least $1 - \delta$. For example, with probability 0.99, for 99% of the subsets of size $k = \max(0, m - 14)$, any assignment can be achieved.

The main contribution of this article over the earlier proceedings version [12] is a technique for constructing k-universal circuits deterministically. Such a deterministic construction obviously guarantees a concrete value of k with probability 1. Specifically, the deterministic construction guarantees k-universality with a circuit that has $k \cdot \lceil \log n \rceil$ inputs, which is not as good as the $O\left(k \cdot \left\lceil \log \frac{n}{k} \right\rceil\right)$ that is achieved by the random construction, with high probability. In fact it guarantees more than that: that every combination with up to k '1'-s is possible. On the other hand no combination with more than k '1'-s is possible, a restriction that does not exist in the random construction. Our contribution in this direction is so far only theoretical, however: it is left for future work to implement and compare it with the random construction on real benchmarks.

In Section 5 we describe our experiments, which attempt to check whether k-universality can be useful in the context of model-checking. In other words, whether the freedom on the original inputs as guaranteed by this method is indeed helpful

[1] In the context of SAT this is less obvious because SAT does not distinguish between inputs and other variables. But the reduction in the number of inputs implies that it has a smaller upper-bound on the size of the smallest back-door set [10], namely the inputs, which suggest a better upper-bound on the run-time.

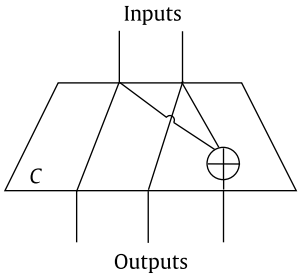

Fig. 2. A 2-universal circuit.

in detecting bugs in real designs, in comparison to other forms of underapproximation that have the same search-space. The answer is conclusive: it is able to find bugs with far fewer inputs. The results are less conclusive, but still positive, when it comes to comparing to a run without underapproximation at all. This is probably due to the fact that our construction is based on a XOR function, which is notoriously hard for SAT solvers. We conclude in Section 6 by pointing to several practical and theoretical issues in applying this method that are still open.

2. Local universality

2.1. k-universal circuits and upper-bound on k

Let C be a Boolean circuit with m inputs and n outputs, $m \leqslant n$, implementing a corresponding function $C : \{0,1\}^m \to \{0,1\}^n$.

Definition 1 (k-universal functions)**.** The function C is *k-universal* if for every subset $K \subset \{1,\ldots,n\}$ of k outputs and every partial assignment $\alpha_K \in \{0,1\}^k$ on K, there is a full assignment $\alpha \in \{0,1\}^m$ on the inputs of C such that $C(\alpha)|_K = \alpha_K$.

In other words, any subset of k output bits can take all 2^k possible assignments in a k-universal function C.

Example 1. The following function $C : \{0,1\}^2 \to \{0,1\}^3$ is 2-universal, since every two output coordinates have all four values:

$$\begin{array}{lcl} C(00) & = & 000 \\ C(01) & = & 011 \\ C(10) & = & 101 \\ C(11) & = & 110. \end{array} \tag{1}$$

This function is implemented by the circuit C in Fig. 2.

In Section 3 we present a methods for constructing k-universal circuits.

2.2. Universality of some known underapproximations

Underapproximations based on restricting the inputs can be seen as functions mapping inputs of the restricted model to inputs of the original model. It is worthwhile to check how universal these functions are. Recall that if the model is unrestricted, it is n-universal, where n is the number of inputs.

- *Underapproximation by restricting a subset of the inputs to constant values*. Regardless of the method for choosing these inputs and their values, or whether it is part of a refinement process or not, it is clear that the underlying set of possible assignment vectors to the restricted model is not even 1-universal, since there are inputs that cannot have both values.
- *Underapproximation by combining inputs*. In this method the set of inputs is partitioned, and all inputs in the same partition class are forced to agree on their value. Regardless of the partitioning method, this method guarantees 1-universality, but not 2-universality, because two inputs in the same partition class cannot have all 4 valuations.

3. The PRG-like construction

The structure of our k-universal circuits, as mentioned earlier, were inspired by constructions of Pseudo Random Generators. PRG is a circuit that, given a short sequence of truly random bits, outputs a longer sequence of pseudo random bits. More formally:

Definition 2 (PRG)**.** Pseudo Random Generator (PRG) is a deterministic polynomial time function $G : \{0,1\}^m \to \{0,1\}^n$, where $n > m$, such that the following distributions are not distinguishable by circuits of size n:

- Distribution G_n defined as the output of function G on a uniformly selected input in $\{0,1\}^m$.
- Distribution U_n defined as the uniform distribution on $\{0,1\}^n$.

The original motivation for constructing PRG's was derandomizing probabilistic algorithms.[2]

In this section we sketch briefly how the original PRG of [13] is constructed, and introduce a slightly different (random) construction that, as we prove later, provides with arbitrarily high probability, k-universal circuits. The parameter k here is almost linear in m, with practically small coefficients. Without going into the details, based on a result in [14] it can be shown that $(2^k \log n \leqslant 2^m)$, which means that an upper-bound on k is $m - \log\log n$. Hence, the circuit we construct has nearly optimal parameters.

Definition 3 (*System*[3])**.** A family $S = (S_1, S_2, \ldots, S_n)$ of equally-sized subsets $S_i \subset \{1, 2, \ldots, m\}$ is a (l, ρ, m, n)-*system* if

- $\forall i,\ |S_i| = l$.
- $\forall i, j\ |S_i \cap S_j| \leqslant \rho$.

Given a Boolean function $f : \{0,1\}^l \to \{0,1\}$ and a (l, ρ, m, n)-system $S = (S_1, S_2, \ldots, S_n)$, we construct the circuit $C = C(S, f)$ as follows:

- $I_C = \{i_1, \ldots, i_m\}$ are the inputs of C.
- $O_C = \{o_1, \ldots, o_n\}$ are the outputs of C.
- For $j \in \{1, \ldots, n\}$,
  - Let $I(o_j) = \{i_h : h \in S_j\}$ be a set of l inputs chosen according to the system S.
  - Set $o_j = f(I(o_j))$.

In the original paper [13] the existence of systems with "good" parameters is proved, and the PRG's are constructed based on these "good" systems using functions f that have some specific cryptographic properties. Further details are given in the above reference.

Now we define our random systems, based on which we will build k-universal circuits.

Definition 4 (Random system)**.** Let n, m be naturals such that $1 \leqslant m \leqslant n$. An (m, n)-*random system* is a family $RS = (S_1, S_2, \ldots, S_n)$ of n uniformly chosen random subsets $S_i \subset \{1, 2, \ldots, m\}$. Namely, for every $1 \leqslant i \leqslant n$ (independently of each other), the set S_i is chosen uniformly at random out of all 2^m possible subsets of $\{1, 2, \ldots, m\}$.

Similarly to the previous construction, we build the circuit $C = C(RS, f)$ where we set f to be the XOR function ($\oplus$). Formally,

- $I_C = \{i_1, \ldots, i_m\}$ are the inputs of C.
- $O_C = \{o_1, \ldots, o_n\}$ are the outputs of C.
- For $j \in \{1, \ldots, n\}$,
  - Let $I(o_j) = \{i_h : h \in S_j\}$ be the randomly chosen set of inputs from RS.
  - Set $o_j = \oplus(I(o_j))$.

In the following section we prove that with arbitrary high probability these circuits are k-universal for relatively high k.

3.1. Lower-bounds on k

First we prove that if the family RS has certain algebraic properties, then the circuit C that is built from RS is k-universal.

Lemma 1. *Let A be an $n \times m$ Boolean matrix defined by the family RS. Formally, the entry $a_{ij} \in A$ is 1 if $j \in S_i$ and 0 otherwise. Then if every k rows of A are linearly independent,[4] the circuit $C = C(RS, \oplus)$ as above is k-universal.*

Proof (Of Lemma 1)**.** First notice that the i'th output of C implements a XOR function on the inputs that correspond to the '1' entries of the i'th row in the matrix A. So we can think of C as a linear transformation in field $GF(2)$ (Galois Field), induced

[2] For instance, a "perfect" PRG would be a function $G : \{0,1\}^{\log n} \to \{0,1\}^n$. If we have such a PRG, then we can deterministically simulate any probabilistic algorithm by going over all $2^{\log n} = n$ possible seeds for G, running the probabilistic algorithm and taking the majority vote.

[3] In the original terminology this set system is called a *Design*. We avoid this term to prevent ambiguity.

[4] Equivalently, every k rows of A form a full rank matrix.

by multiplying the matrix A with the input vector (recall that addition in $GF(2)$ is equivalent to the XOR operator). In other words, for every $\alpha_1\alpha_2\cdots\alpha_m \in \{0,1\}^m$ and $\beta_1\beta_2\cdots\beta_n \in \{0,1\}^n$, $C(\alpha_1\alpha_2\cdots\alpha_m) = \beta_1\beta_2\cdots\beta_n$ if and only if the following holds:

$$\begin{pmatrix} a_{11} & a_{12} & \dots & a_{1m} \\ a_{21} & a_{22} & \dots & a_{2m} \\ \cdot & & & \cdot \\ \cdot & & & \cdot \\ \cdot & & & \cdot \\ a_{n1} & a_{n2} & \dots & a_{nm} \end{pmatrix} \times \begin{pmatrix} \alpha_1 \\ \alpha_2 \\ \vdots \\ \alpha_m \end{pmatrix} = \begin{pmatrix} \beta_1 \\ \beta_2 \\ \cdot \\ \cdot \\ \cdot \\ \beta_n \end{pmatrix}. \tag{2}$$

Let $K = \{o_1, o_2, \dots, o_k\} \subset \{1, 2, \dots, n\}$ be an arbitrary set of k outputs, and let $\beta_{o_1}\beta_{o_2}\cdots\beta_{o_k}$ be any partial assignment on K. Notice that for any $\alpha_1\alpha_2\cdots\alpha_m$ the value $C(\alpha_1\alpha_2\cdots\alpha_m)$ restricted to K equals $\beta_{o_1}\beta_{o_2}\cdots\beta_{o_k}$ if and only if

$$\begin{pmatrix} a_{o_1 1} & a_{o_1 2} & \dots & a_{o_1 m} \\ a_{o_2 1} & a_{o_2 2} & \dots & a_{o_2 m} \\ \cdot & & & \cdot \\ \cdot & & & \cdot \\ \cdot & & & \cdot \\ a_{o_k 1} & a_{o_k 2} & \dots & a_{o_k m} \end{pmatrix} \times \begin{pmatrix} \alpha_1 \\ \alpha_2 \\ \vdots \\ \alpha_m \end{pmatrix} = \begin{pmatrix} \beta_{o_1} \\ \beta_{o_2} \\ \cdot \\ \cdot \\ \cdot \\ \beta_{o_k} \end{pmatrix}. \tag{3}$$

We denote this restricted $k \times m$ matrix by B. Recall that our purpose is to prove that such an assignment $\alpha_1\alpha_2\cdots\alpha_m$ indeed exists. Here we use the fact that every k rows in A are linearly independent, and thus the matrix B is invertible. Therefore such an assignment exists, and it can be computed by:

$$\begin{pmatrix} \alpha_1 \\ \alpha_2 \\ \vdots \\ \alpha_m \end{pmatrix} = \begin{pmatrix} a_{o_1 1} & a_{o_1 2} & \dots & a_{o_1 m} \\ a_{o_2 1} & a_{o_2 2} & \dots & a_{o_2 m} \\ \cdot & & & \cdot \\ \cdot & & & \cdot \\ \cdot & & & \cdot \\ a_{o_k 1} & a_{o_k 2} & \dots & a_{o_k m} \end{pmatrix}^{-1} \times \begin{pmatrix} \beta_{o_1} \\ \beta_{o_2} \\ \cdot \\ \cdot \\ \cdot \\ \beta_{o_k} \end{pmatrix}. \quad \square \tag{4}$$

The next lemma states that with probability $1-\delta$ (where $\delta > 0$ is an arbitrary confidence parameter), in the matrix A defined by the family RS, every k rows are linearly independent.

Lemma 2. *Let $k > 1$ be a natural number and let $\delta > 0$ be a fixed confidence parameter. Set $b = m/k$ and $a = n/m$. Let RS be a family of subsets in (m, n)-random system and let A be the underlying matrix as above. If the inequality $b > \log(e \cdot ab(1/\delta)^{1/k}) + 1$ is satisfied by the above parameters, then with probability at least $1-\delta$ (over the construction of RS) every k rows in A are linearly independent.*[5]

Before proving the lemma, we list some known useful inequalities:

(i) Let $x_1, x_2, \dots, x_n$ be non-negative reals. Then $\prod_{i=1}^{n}\Big(1 - x_i\Big) > 1 - \sum_{i=1}^{n} x_i$.

(ii) $\binom{n}{k} < (\frac{en}{k})^k$.

(iii) Let m, k be naturals such that $m > k$. Then $\sum_{i=1}^{k} 2^{i-m} \leqslant 2 \cdot 2^{k-m}$.

Proof (*of Lemma 2*)**.** According to the construction of random systems, every row in A is a random Boolean vector of length m. Let $K = \{o_1, o_2, \dots, o_k\} \subset \{1, 2, \dots, n\}$ be any sequence of k rows in A. Now we define a sequence of "bad" event indicators: $I_j = 1$ if and only if the j'th row $o_j \in K$ is a linear combination of the rows $o_1, \dots, o_{j-1}$. Obviously if $(\sum_{j=1}^{k} I_j) = 0$ then the rows in K are linearly independent. Note that in every step j, the $j-1$ preceding vectors span a linear space of size at most 2^{j-1}. Since the rows of A are chosen uniformly at random (independently of each other), we have $\Pr[I_j = 0] \geqslant \frac{2^m - 2^{j-1}}{2^m}$. Therefore,

$$\Pr\Big[\Big(\sum_{j=1}^{k} I_j\Big) = 0\Big] = \prod_{j=1}^{k} \frac{2^m - 2^{j-1}}{2^m} \tag{5}$$

$$= \prod_{j=1}^{k} (1 - 2^{j-1-m}) \geqslant 1 - \sum_{j=1}^{k} 2^{j-1-m} \geqslant 1 - 2^{k-m}. \tag{6}$$

[5] $e = 2.718\ldots$ is the Euler constant.

The last two inequalities follow from (i) and (iii). We can now conclude that

$$\Pr\left[\left(\sum_{j=1}^{k} I_j\right) > 0\right] \leqslant 2^{k-m}. \tag{7}$$

There are $\binom{n}{k} \leqslant \left(\frac{en}{k}\right)^k$ possible sets of k rows, and by the Union Bound[6] the probability that some set of k rows is not linearly independent is at most

$$\left(\frac{en}{k}\right)^k \cdot 2^{k-m} = (eab)^k \cdot 2^{(1-b)k} \leqslant (eab)^k \cdot 2^{-\log(eab(1/\delta)^{1/k})\cdot k} = \delta. \quad \square \tag{8}$$

Corollary 1. *Let C be a circuit based on a family RS of a random system as described above, with parameters m, n. Let $k > 1$ be a natural number and set $b = m/k$ and $a = n/m$. The circuit C is k-universal with probability at least δ, for any δ that satisfies*

$$b > \log(e \cdot ab(1/\delta)^{1/k}) + 1.$$

Proof. By Lemma 2 we know that with these parameters, in the underlying matrix A every k rows are linearly independent with probability $1 - \delta$ or higher. On the other hand, by Lemma 1 we know that if every k rows in A are linearly independent, then the circuit $C = C(RS, \oplus)$ is k-universal. $\square$

Based on Corollary 1, it is left to show how we construct the underapproximating model M'. The construction is as follows:

- Let $\{i_1, \ldots, i_n\}$ be the primary inputs of M. Construct the k-universal circuit C based on a random system $RS = (S_1, \ldots, S_n)$.
- For each $j \in \{1, \ldots, n\}$, connect the j'th input of M to the j'th output of C.

The inputs of the underapproximating model M' are the m inputs of C.

Understanding the inequality from Corollary 1. It is not immediately clear what is the relation between the universality parameter k and the other parameters from Corollary 1. We try to clarify this relation by making several realistic assumptions and simplifications.

First, we can fix the bound δ on failure probability to $1/100$ and plug in the values of a and b. This gives us the following inequality:

$$\frac{m}{k} > \log\left(e \cdot \frac{n}{k} 100^{1/k}\right) + 1,$$

or equivalently,

$$m > k \cdot \left(\log e + \log n - \log k + \frac{\log 100}{k} + 1\right).$$

Notice that when k is larger than 8, this is equivalent to

$$m > k \cdot (\log n - \log k + 3).$$

In other words, the universality parameter k can get as large as

$$\frac{m}{\log n - \log k + 3} \approx \frac{m}{\log\left(\frac{n}{k}\right)},$$

and still, the condition in Corollary 1 will be satisfied.

Since m (the number of inputs) is always larger than the universality parameter k, we can express the bound on the universality parameter explicitly by replacing k with m on the right hand side, i.e., as long as

$$k \leqslant \frac{m}{\log n - \log m + 3},$$

the condition of Corollary 1 is satisfied.

As we demonstrate in our experimental results (see Section 5), in most of the cases the best improvement is achieved when $m \approx \frac{n}{5}$, so in this case k is approximately $m/6$.

Sample values of universality. It is worthwhile to see some values of k given n, m and δ. For instance, for $n = 140$, $m = 70$ and $\delta = 0.02$ we can get $k = 10$-universality with probability at least 0.98. This means that we can reduce the number of inputs to the model by half, and still get 10-universality with a very high probability.

[6] Union Bound: for a countable set $A_1, A_2, A_3, \ldots$ of events, $\Pr\left[\bigcup_i A_i\right] \leqslant \sum_i \Pr\left[A_i\right]$.

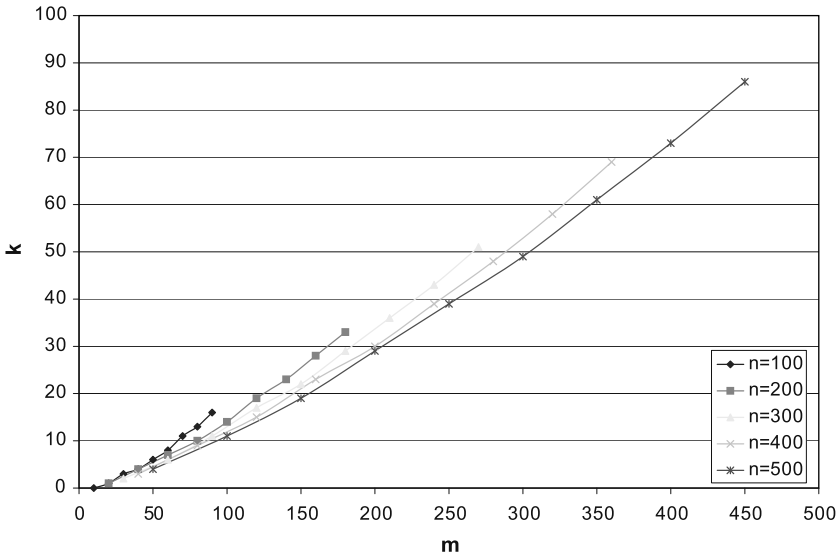

Fig. 3. The value of k for different values of m and n, and a fixed value of δ (0.02).

In general δ has a very small effect on k, hence the probability of success can be made very close to 1. The chart in Fig. 3 refers to a fixed value $\delta = 0.02$. The chart shows the value of k for $n = 100, 200, \ldots, 500$, where m is sampled 9 times for each value of n, in the range $n/10 \ldots 9n/10$. It is clear from the graph that k is close to linear in m, and that it has a constant factor of about 5. In fact, the equation $b = \log(e \cdot ab(1/\delta)^{1/k}) + 1$ from Lemma 2 implies that $k \sim \frac{m}{\log(n/k)}$, which means that k is linear in m for all practical n.

3.2. A better lower-bound on k for "almost" k-universality

In practice, given n and m the parameter of universality (k) is expected to be significantly higher than what our analytic lower bound provides. But it is quite challenging to estimate the gap between the lower-bound and the actual values of k, since checking k universality of a circuit $C : \{0,1\}^m \to \{0,1\}^n$ is hard for reasonably large n, m and k. But if we slightly relax our notion of universality we can get much better bounds on k. Formally, let m, n, k and $C = C(RS, \oplus)$ be as above. Given a subset $K \subset \{1, \ldots, n\}$ of k outputs, we say that the subset K is *covered* by C if for all partial assignments $\alpha_K \in \{0,1\}^k$ on K, there is a full assignment $\alpha \in \{0,1\}^m$ on the inputs of C such that $C(\alpha) \mid_K = \alpha_K$. For any parameter $0 < \epsilon \leqslant 1$ we can define a relaxed notion of universality as follows.

Definition 5 ((k,ϵ)-universality)**.** A circuit C is (k,ϵ)-universal if at least $(1-\epsilon)\binom{n}{k}$ subsets $K \subset \{1, \ldots, n\}$ of k outputs are covered by C.

Recall that our previous bounds on k were valid for circuits that cover *all* $\binom{n}{k}$ subsets K, i.e., $(k,0)$-universal circuits. The following lemma gives another lower-bound on k, which is significantly better than the previous one as long as the parameter ϵ is not too small.

Lemma 3. *Let $m < n$ be naturals and let $C = C(RS, \oplus)$ be a circuit as defined above. Fix $0 < \epsilon, \delta \leqslant 1$ and set $k = \max(0, m - \log \frac{1}{\epsilon \cdot \delta})$. The circuit C is (k,ϵ)-universal with probability at least $1 - \delta$.*

Consequently, for any $0 < \epsilon < 1$ and $k \leqslant \max(0, m - 2\log \frac{1}{\epsilon})$, the circuit C is (k,ϵ)-universal with probability at least $1 - \epsilon$.

Observe the implication of this result: since m is an absolute upper-bound on k, it means that with a small sacrifice of universality and confidence we obtain a value close to this theoretical limit. For example, for $\delta = \epsilon = 0.1$ (and $m \geqslant 7$), we get $k = m - 7$, i.e., with probability at least 0.9, the circuit C is $(\max(0, m-7), 0.1)$-universal. Now consider a negligible sacrifice and failure probability, such as $\delta = \epsilon = 0.01$. In this case we get $(k, 0.01)$-universality for $k = \max(0, m - 14)$.

Proof (*of Lemma 3*)**.** The proof is a simple application of Markov's inequality[7] on one of the consequences from the proof of Lemma 2. For every subset $K \subset \{1, 2, \ldots, n\}$ of size k, we define X_K as a random 0, 1 variable, such that $X_K = 1$ if and only

[7] Markov inequality: let X be a random variable assuming only non-negative values. Then for all $c > 0$, $\Pr\left[X \geqslant c \cdot E[X]\right] \leqslant \frac{1}{c}$.

if the subset K is *not* covered by C. Referring to the proof of Lemma 1, the set K is covered by C if and only if the sub-matrix B that corresponds to K has full rank (otherwise the linear transformation is not injective). Then from the proof of Lemma 2 we have $\Pr[X_K = 1] \leqslant 2^{k-m}$. Now let

$$X = \sum_{K \subset \{1,\ldots,n\}, |K|=k} X_K,$$

be the sum of these variables. By linearity of expectation,[8]

$$E[X] = \sum_K E[X_K] \leqslant \binom{n}{k} \cdot 2^{k-m}, \tag{9}$$

and by Markov's inequality,

$$\delta = \Pr\left[X \geqslant \epsilon \cdot \binom{n}{k}\right] = \Pr\left[X \geqslant \epsilon \cdot 2^{m-k} \cdot \binom{n}{k} \cdot 2^{k-m}\right] \leqslant \frac{1}{\epsilon \cdot 2^{m-k}}. \tag{10}$$

From (10) we derive $k \geqslant m - \log \frac{1}{\epsilon \cdot \delta}$. □

4. Constructing universal circuits deterministically

In this section we describe a deterministic method for constructing universal circuits. It has both advantages and disadvantages in comparison to the probabilistic method. The advantages are:

- The construction is deterministic, and hence the universality parameter is known in advance and guaranteed.
- The constructed circuit does not use XOR gates and hence is expected to burden the solver less.

The disadvantage is:

- The universality parameter k is smaller than in the random construction, with respect to a similar value of m. Specifically, $m = k \cdot \lceil \log n \rceil$ rather than $m = O(k \cdot \left\lceil \log \frac{n}{k} \right\rceil)$ as in the random construction.

The following is a short description of the circuit construction, for a given goal universality value k:

1. The circuit has $m = k \cdot \lceil \log n \rceil$ inputs. These inputs are clearly sufficient for generating any combination of k numbers $N_0, \ldots, N_{k-1}$ in the range $0, \ldots, n-1$.
2. Define each output of the circuit O_j for $j \in \{0, \ldots, n-1\}$ as follows:

$$O_j \doteq \bigvee_{i=0}^{k-1} N_i = j. \tag{11}$$

That is, an output O_j is set to TRUE if and only if one (or more) of the k numbers is set to the value j.

The resulting circuit is k-universal because of the complete freedom in choosing the input numbers $N_0, \ldots, N_{k-1}$. In fact the circuit allows every valuation of the outputs as long as it does not contain more than k '1'-s, and forbids all other valuations. Thus, what it allows is more than is expected with high probability from the random construction and more than required by k-universality, but what it forbids implies that more than k-universality is impossible (a restriction that does not exist in the random construction).

In the rest of this section we formalize this idea.

4.1. Functions that imply universality

For a binary string $\alpha \in \{0,1\}^n$ we denote by $|\alpha|$ the weight of α, i.e., the number of ones in α. We denote by $\{0,1\}^n_{\leqslant k}$ the set

$$\left\{\alpha \in \{0,1\}^n : |\alpha| \leqslant k\right\}.$$

Let m and n be two natural numbers that satisfy $n > m$. Given a function $f : \{0,1\}^m \to \{0,1\}^n$, we say that f *covers* all vectors of weight up to k if the following holds:

$$\{0,1\}^n_{\leqslant k} \subseteq \mathit{image}(f), \tag{12}$$

namely, for every $\alpha \in \{0,1\}^n_{\leqslant k}$ there exists $\beta \in \{0,1\}^m$ such that $f(\beta) = \alpha$.

[8] Linearity of expectation: for any n random variables $X_1, \ldots, X_n$ the following holds: $\mathrm{E}\left[\sum_{i=1}^n X_i\right] = \sum_{i=1}^n \mathrm{E}[X_i]$.

Lemma 4. *Any function $f : \{0,1\}^m \to \{0,1\}^n$ that covers all vectors of weight up to k is in addition k-universal.*

Proof. Recall that the definition of k-universality requires that for any subset $K \subset \{0,\ldots,n-1\}$ of k indices, and any partial assignment $\alpha' \in \{0,1\}^k$ on the indices in K, there exists $\beta' \in \{0,1\}^m$ such that $f(\beta')|_K = \alpha'$. Now consider the string $\alpha \in \{0,1\}^n$ that agrees with the partial assignment α' on the indices in K, and has all zeroes outside of K. Clearly $|\alpha| \leqslant k$, thus from the definition above we know that there exists $\beta \in \{0,1\}^m$ such that $f(\beta) = \alpha$, and consequently $f(\beta)|_K = \alpha'$. □

4.2. Implementing the covering functions

According to Lemma 4, in order to construct k-universal circuits it is enough to construct a circuit C_f which implements a function $f : \{0,1\}^m \to \{0,1\}^n$ that covers all vectors of weight up to k. Note that the size of the range of such an f must be at least $\sum_{i=0}^{k}\binom{n}{i}$, and that to generate this many values the parameter m must satisfy

$$m \geqslant \log\left(\sum_{i=0}^{k}\binom{n}{i}\right) \geqslant \log\binom{n}{k} \geqslant k(\log n - \log k). \tag{13}$$

(the last step is based on the known inequality $\binom{n}{k} \geqslant (n/k)^k$).
Isolating k yields:

$$k \leqslant \left\lfloor \frac{m}{\log n - \log k} \right\rfloor. \tag{14}$$

Recall that we are interested in maximizing the universality parameter k with respect to m and n. This can be done explicitly by implementing the truth table of any given function f in Disjunctive Normal Form or Conjunctive Normal Form. But such a construction is highly inefficient, and may result in a circuit of exponential size.

The construction that follows, on the other hand, yields a circuit of size $O(n \cdot k \cdot \log n)$ but achieves slightly weaker universality, i.e.

$$k = \frac{m}{\lceil \log n \rceil}. \tag{15}$$

Recall that the theoretical upper-bound on the universality parameter is $k \leqslant m$. Thus, for practical values of n this result is still quite close to the optimum, although not as close as the one achieved from the random construction.

In the following, for any binary string $\beta \in \{0,1\}^\ell$ denote by $N_\beta \in \{0,\ldots,2^\ell - 1\}$ the natural number whose binary representation is β (note that this overloads the notation N).

We now set $m = k\lceil \log n \rceil$ and define the function $f_I : \{0,1\}^m \to \{0,1\}^n$ that we are going to implement. For any $\alpha \in \{0,1\}^m = \{0,1\}^{k\lceil \log n \rceil}$ we split α into k parts $\beta_0, \beta_2, \ldots, \beta_{k-1}$, each of length $\lceil \log n \rceil$, and set

$$f_I(\alpha) = f_I(\beta_0\beta_1\cdots\beta_{k-1}) = b_0 b_1 b_2 \cdots b_{n-1}, \tag{16}$$

where for each $i \in \{0,\ldots,n-1\}$, $b_i = 1$ if and only if for some j, $N_{\beta_j} = i$.

It is easy to verify that the function f_I covers all vectors of weight up to k (in fact, the range of f_I contains only these vectors). Therefore, according to Lemma 4, f_I is a k-universal function. The only thing left to do is to build a circuit C_f that implements the function f_I. This can be done as follows:

1. Let i be a number in the range $\{0,\ldots,n-1\}$. Let S be a vector of $\lceil \log n \rceil$ inputs, and let α be a binary string of the same length, such that $N_\alpha = i$. For $s \in S$ let $\alpha(s)$ be the Boolean value in α corresponding to the input s. Define

$$s(\alpha) \doteq \begin{cases} s & \alpha(s) = 1 \\ \neg s & \alpha(s) = 0 \end{cases}. \tag{17}$$

   Let

$$C_i(S) \doteq \bigwedge_{s\in S} s(\alpha). \tag{18}$$

   Thus, $C_i(S)$ is a circuit that evaluates to '1' if and only if the valuation of its inputs S correspond to N_i. For example, for $i = 2$ (hence $\alpha = 10$) and $S = i_0 i_1$, $C_i(S) = i_0 \wedge \neg i_1$.
2. Split the inputs $\{i_0,\ldots,i_{k\lceil \log n \rceil - 1}\}$ into $S_0, S_1, \ldots, S_{k-1}$, which are k disjoint binary vectors of size $\lceil \log n \rceil$ each.
3. For each $i \in \{0,\ldots,n-1\}$, connect the i'th output of C_f to

$$C_f^i \doteq \bigvee_{j=0}^{k-1} C_i(S_j). \tag{19}$$

#	n	S	(PRG) $m = \ldots$			
			$n/2$	$n/3$	$n/5$	$n/10$
1	45	96	66	63	66	63
2	76	173	149	76	72	68
3	76	191	127	77	79	-
4	85	211	170	121	105	140
5	68	61	65	20	592	-
6	68	73	59	14	661	-
7	68	482	308	46	52	-
8	68	122	152	16	90	-
9	64	2101	1915	1966	1654	1208
10	80	1270	1392	1830	1137	-
11	83	2640	2364	2254	1845	-
12	6	8201	7191	-	-	-
13	60	942	453	432	351	-
14	218	965	735	778	510	396
15	52	1206	-	-	-	-
16	157	953	-	-	-	-
17	68	21503	TO	TO	TO	TO

Fig. 4. Run-times in seconds with the PRG construction. Each row represents a separate hardware design. The second column indicates the number of inputs in the design n. The column S stands for run-times without any underapproximation.

Example 2. Let $n = 4$ and $k = 2$. The circuit thus has 4 outputs, which we denote by $O_0, \ldots, O_3$, and $k \cdot \lceil \log n \rceil = 4$ inputs, denoted $i_0, \ldots, i_3$. The inputs are partitioned from left to right naturally, i.e., $S_0 = i_0 i_1,\ S_1 = i_2 i_3$.

Now define:

$$\begin{aligned} O_0 &= C_0(S_0) \vee C_0(S_1) = (\neg i_0 \wedge \neg i_1) \vee (\neg i_2 \wedge \neg i_3) \\ O_1 &= C_1(S_0) \vee C_1(S_1) = (\neg i_0 \wedge i_1) \vee (\neg i_2 \wedge i_3) \\ O_2 &= C_2(S_0) \vee C_2(S_1) = (i_0 \wedge \neg i_1) \vee (i_2 \wedge \neg i_3) \\ O_3 &= C_3(S_0) \vee C_3(S_1) = (i_0 \wedge i_1) \vee (i_2 \wedge i_3). \end{aligned} \tag{20}$$

The number of gates required to implement every C_f^i is bounded by $O(k \cdot \lceil \log n \rceil)$, and the total size of C_f is at most $O(n \cdot k \cdot \lceil \log n \rceil)$, as promised.

In a technical report [15] we show that this construction can be improved further and achieve a ratio $m = k \cdot \lceil \log(n - k + 1) \rceil$.

5. Experimental results

All experiments reported in this section refer to the random construction. We interfaced our tool with IBM's model-checker RuleBase. We experimented with bounded model-checking of 17 different real designs (after RuleBase has applied numerous optimizations on them in the front-end, hence the relatively small number of inputs) that had previously known bugs. The tables show our results *without* an automatic refinement procedure. The reason we are giving the tables in this form is that we want to show the influence of m on run-time and chances to find the bug with each underapproximation technique. The tables show run-times in seconds until detecting the bug, for different values of m, where m in all techniques represent the number of inputs to the underapproximated model. A sign '-' denotes that the bug was not found up to a bound of 100. 'TO' denotes a timeout of 6 h.

The table in Fig. 4 summarizes results with our construction, hence m is the number of inputs to the circuit. The column S denotes run-time with no underapproximation. It is clear from this table that while $m = n/10$ is too low, $m = n/5$ is high enough to find the bug in 13 out of 17 cases, and typically in less time comparing to the S column, despite the complexity of the XOR function in the PRG-like circuit. Thus, our refinement procedure is set to begin with this value. The last three designs indicate that there are cases in which underapproximation does not work (in all three methods – see Fig. 5 as well). Since RuleBase activates various engines in parallel, this is not a serious issue: the contribution of a tool is mainly measured by the number of wins rather than by the average run-time. This is also the reason it is acceptable that such a method has no value if the design satisfies the property.

In Fig. 5 we show results for the two alternative underapproximations described in Section 2.2. It is clear from these tables that universality matters: both of these underapproximations need far more inputs than the PRG construction in order to find the bug. Somewhat surprisingly even in the cases they are able to find the bug, they do so in time comparable or longer than without underapproximation at all. The reason seems to be that the underapproximation delays the finding of the bug to deeper cycles, which in general affects negatively the run-time of SAT.

#	n	S	(FIX) $m = \ldots$				(Group) $m = \ldots$			
			$n/2$	$n/3$	$n/5$	$n/10$	$n/2$	$n/3$	$n/5$	$n/10$
1	45	96	246	-	-	-	223	229	227	231
2	76	173	-	-	-	-	361	446	-	-
3	76	191	373	-	-	-	168	317	-	-
4	85	211	191	317	-	-	306	289	405	-
5	68	61	-	-	-	-	410	-	-	-
6	68	73	-	-	-	-	-	-	-	-
7	68	482	-	-	-	-	561	491	-	-
8	68	122	-	-	-	-	113	-	-	-
9	64	2101	1693	-	-	-	2150	-	-	-
10	80	1270	-	-	-	-	-	-	-	-
11	83	2640	-	-	-	-	-	-	-	-
12	6	8201	-	-	-	-	-	-	-	-
13	60	942	1206	-	-	-	413	407	-	-
14	218	965	-	-	-	-	969	1102	-	-
15	52	1206	-	-	-	-	-	-	-	-
16	157	953	-	-	-	-	-	-	-	-
17	68	21503	-	-	-	-	TO	-	-	-

Fig. 5. Run-times in seconds when (left) fixing $n - m$ inputs to an arbitrary value and (right) grouping the inputs into m sets, and forcing inputs in the same set to be equal. The column S stands for run-times without any underapproximation. Here decreasing the number of inputs seems to have less predictable effect on the run-time of SAT. The run-time can increase, possibly because less inputs imply less satisfying assignments. See Section 2.2 for more details on these underapproximations.

$p =\rightarrow$	1/2	1/3	1/5	1/10
$m = n/2$	0	0	0	0
$m = n/3$	0	0	0	0
$m = n/5$	0	0	0	0
$m = n/10$	0	0	0	1

Fig. 6. The accumulative number (over four designs) of cycles by which the shallowest bug is delayed, as a function of the number of inputs m and the probability p to choose each such input for inclusion in the XOR function. As can be seen in the table. Only in one design, in the most extreme case, the bug was delayed by one cycle.

To test the impact of m, the number of inputs, and p, the probability to choose to include an input in the XOR function, we checked four of the designs that happened to still find the error even with $m = n/10$, with different values of m and p. The goal was to see by how many cycles the depth of the shallowest bug is delayed by, as a function of these parameters. The accumulative results appear in Fig. 6. Only in one design, when m was set to 10% of the inputs and p to a probability of 0.1, the error was delayed by one cycle. This confirms our hypothesis, at least with respect to those designs that we checked, that the values of only few inputs matter for exposing errors in real life designs.

6. Conclusion and future work

Relying on k-universality, we were able to find errors in most industrial case-studies that we tried with a number of inputs as small as one fifth or even one tenth of the original number of inputs. Further, in almost all cases, these errors are found at their original depth. This empirical evidence matches the common knowledge of practitioners that use model-checking in an industrial setting: most errors can be exposed regardless of the values of many of the inputs. The construction of k-universal circuits as proposed in this article can serve as an underapproximating technique that exploits this observation in an automatic, straight-forward way.

We proposed two methods for constructing k-universal circuits, namely the random and deterministic constructions, both of which have their own advantages. The better expected value of k with the random construction suggests that perhaps the best solution is to derandomize the algorithm in the most brute-force way: build a library of matrices corresponding to different values of m and n that are known to have good universality values. The question of how to measure the actual universality of a given circuit is interesting by its own right, and we currently do not know how to check it without explicitly trying all combinations of values for all sets of k outputs.

There are many other directions in which this research can progress. On the empirical side – first and foremost, the deterministic construction technique has to be implemented and compared with the random construction. Second, both constructions have to be evaluated with unbounded model-checking and simulation. Simulation is insensitive to XOR chains, which indicates that it might show a stronger influence on the results. Third, the fact that in bounded model-checking the inputs of each time-frame are represented by different variables can be exploited for reducing the number of inputs m

much more. The PRG construction can be attached to the *unrolled* circuit. This construction will now have m inputs for $0 < m < n \cdot \mathcal{K}$, where $\mathcal{K}$ is the unrolling bound. It is very likely that errors can be found this way with a smaller set of inputs per cycle.

On the theoretical side – the question of efficient refinement is still open. Our current implementation of refinement is very naïve, as it simply increases m. This has a clear disadvantage that it does not rule out combinations of inputs that were already checked in the previous iteration. We could not find so far a reasonable solution to this problem. Another direction of research related to refinement is finding a way to guide the circuit construction according to the previous iterations. Perhaps it is worth while to change the probabilities of various inputs according to the unsatisfiable core of the previous iterations.

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